

Hit residuals from track fitting

**ePIC Track Reconstruction meeting
22 February 2024**

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Motivation

- Study the track reconstruction performance at each layer of the central tracker geometry
- The χ^2 depends on tracking parameters and is not as straightforward as a residual
- There is also an arbitrary χ^2 cut of 15 that separates hits from becoming measurements or outliers

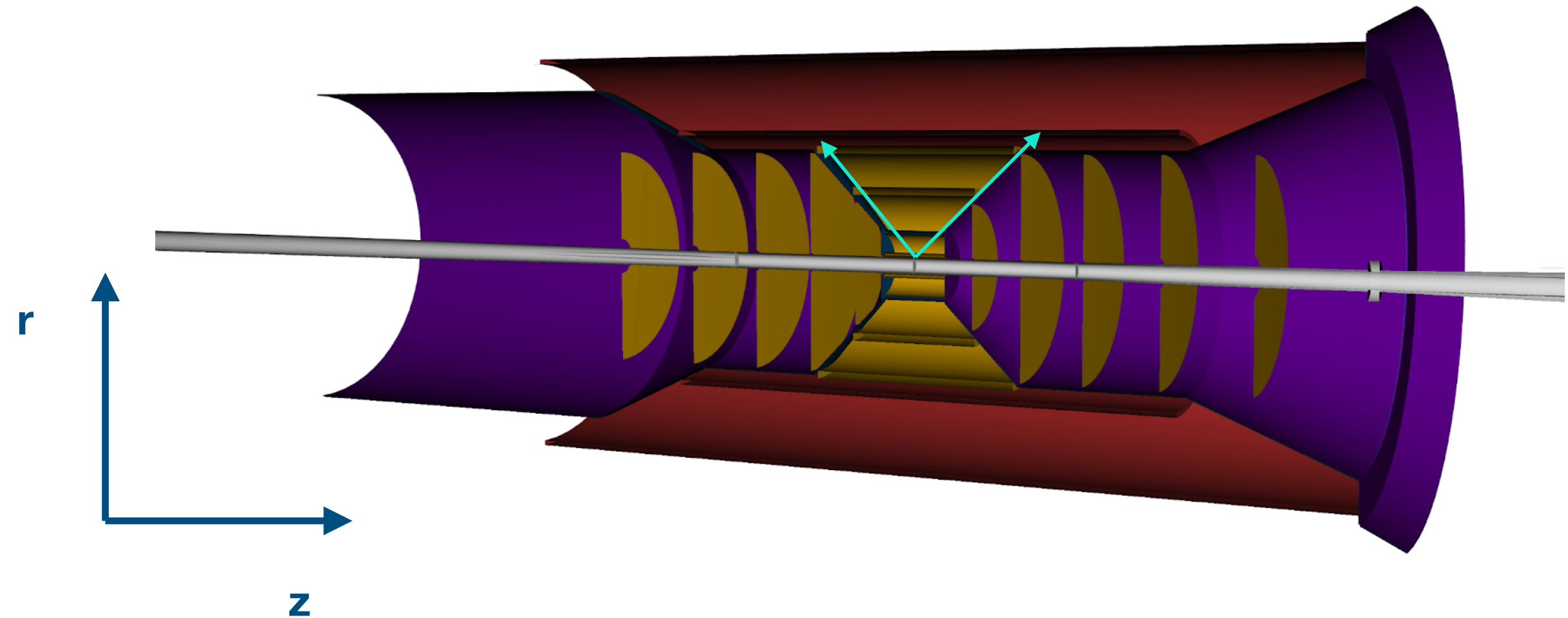
Process

Events used:

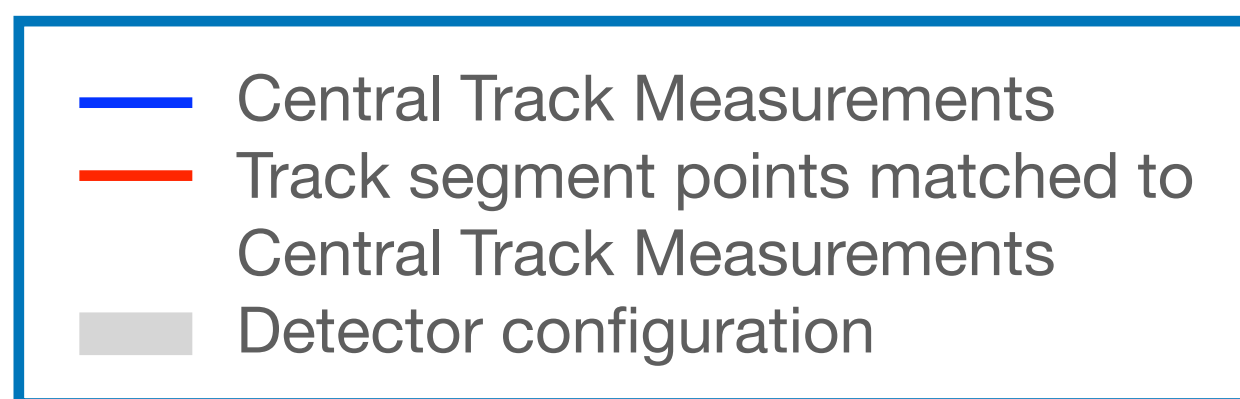
- Single muon events, 10,000 events
- $0.5 < p < 20$ GeV
- Only looking at the central tracker

Calculating residuals:

- Compare the “CentralTrackSegment.points” with the “RecHits” to see how the hits compare to the reconstructed track
- Find the track point with the closest distance to the reconstructed hit in $\Delta r(\Delta z)$ for the barrel(endcap)
- Barrel layer residual = $\Delta z = z_{\text{hit}} - z_{\text{trackpoint}}$
- Endcap layer residual = $\Delta r = r_{\text{hit}} - r_{\text{trackpoint}}$

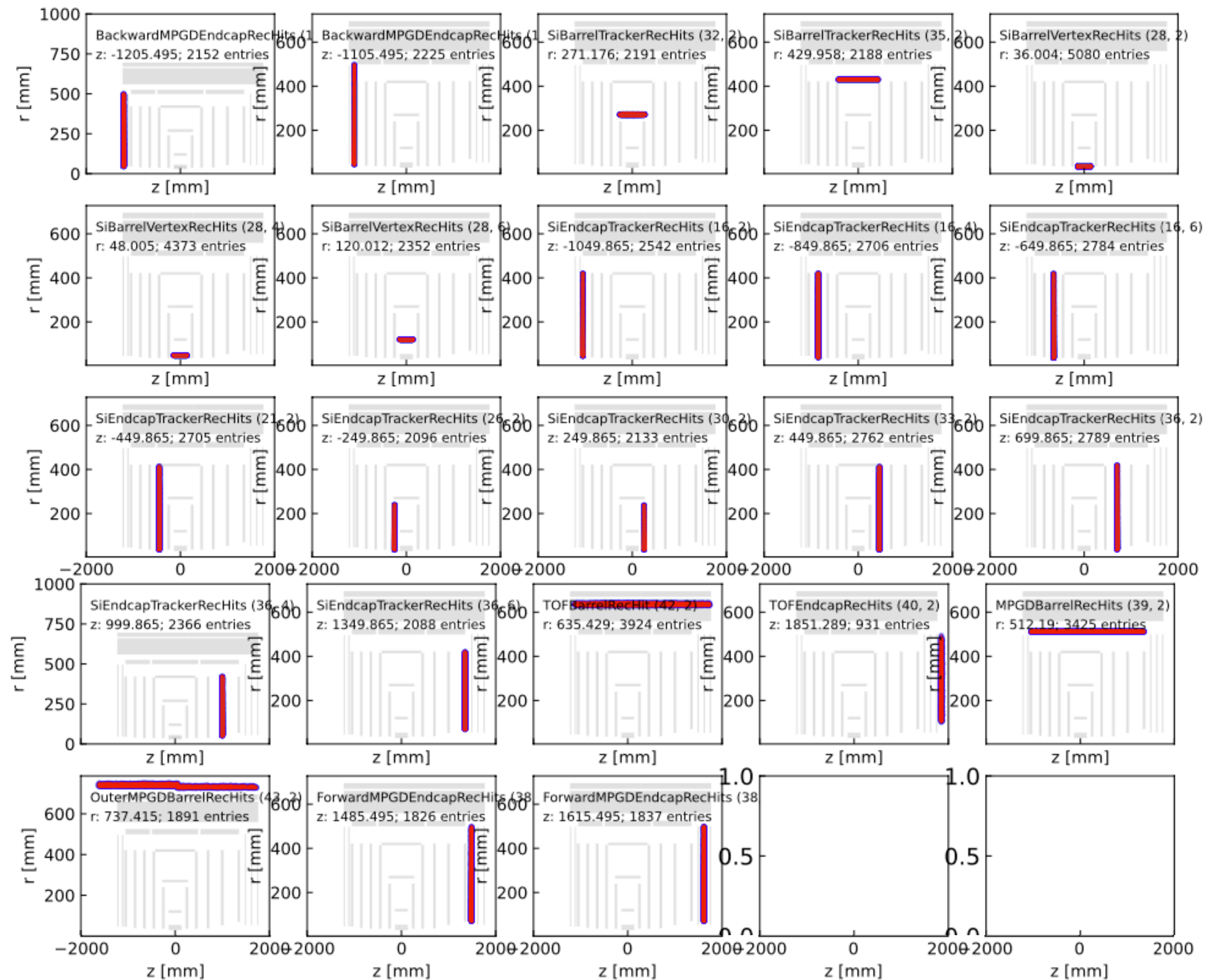


r/z positions per layer



- Visually, it looks like the measurements line up nicely with the track points

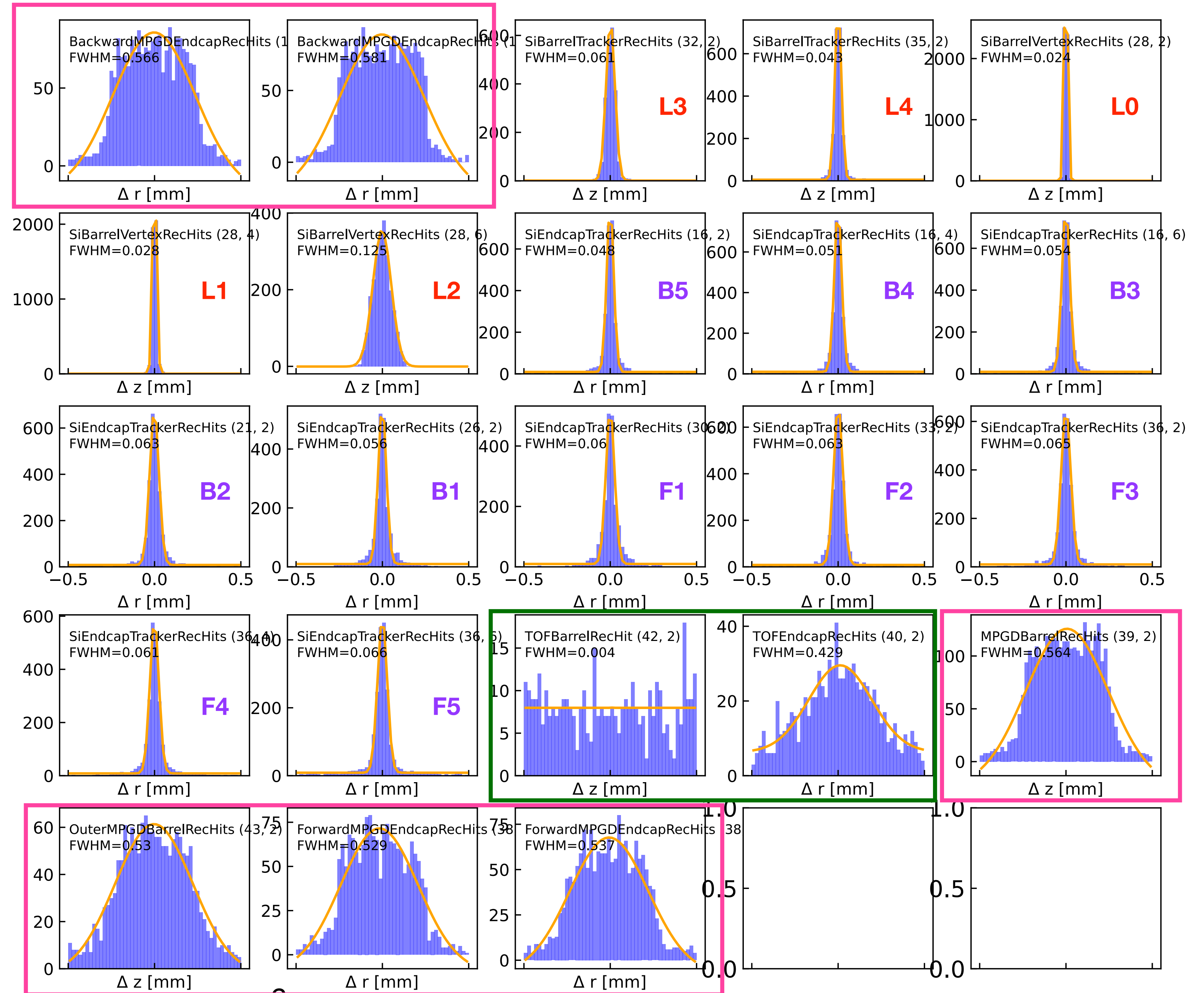
r/z Positions per Layer



Residuals per layer

- Truth seeded, μ^-
- $0.5 < p < 20 \text{ GeV}/c$
- All x-axis ranges are between $-0.5 - 0.5 \text{ mm}$
- Silicon peaks range from a FWHM of $24 - 125 \mu\text{m}$

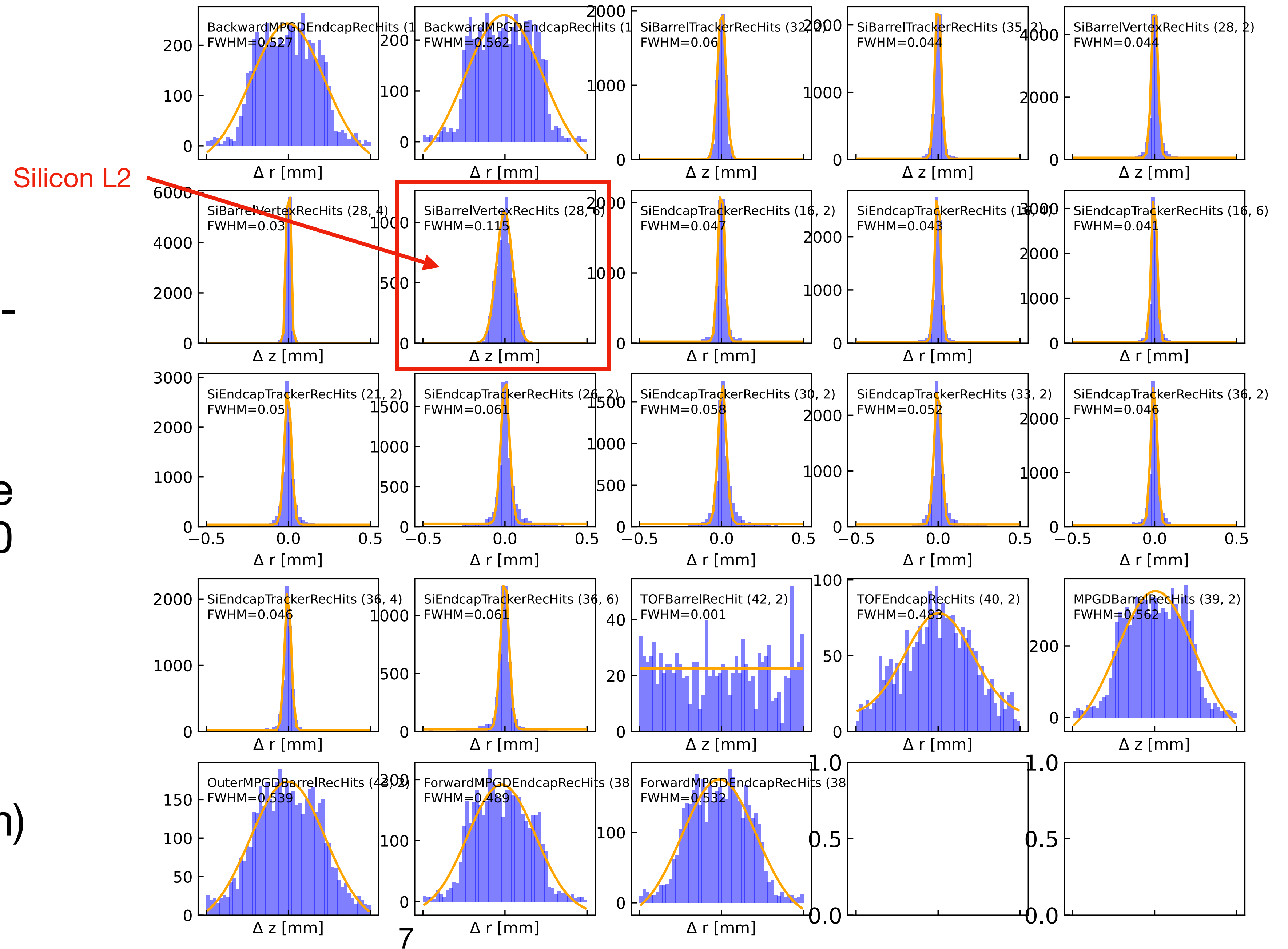
Residuals



Residuals per layer

- Realistic seeded, μ^-
- $0.5 < p < 20 \text{ GeV}/c$
- Silicon peaks range from a FWHM of 30 - 115 μm
- (compared to truth seeded: FWHM ranges from 24 - 125 μm)

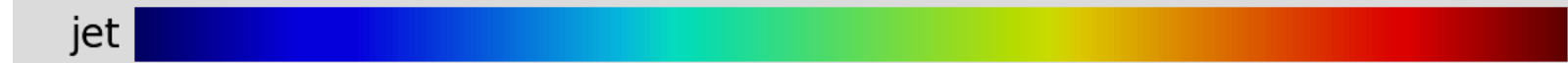
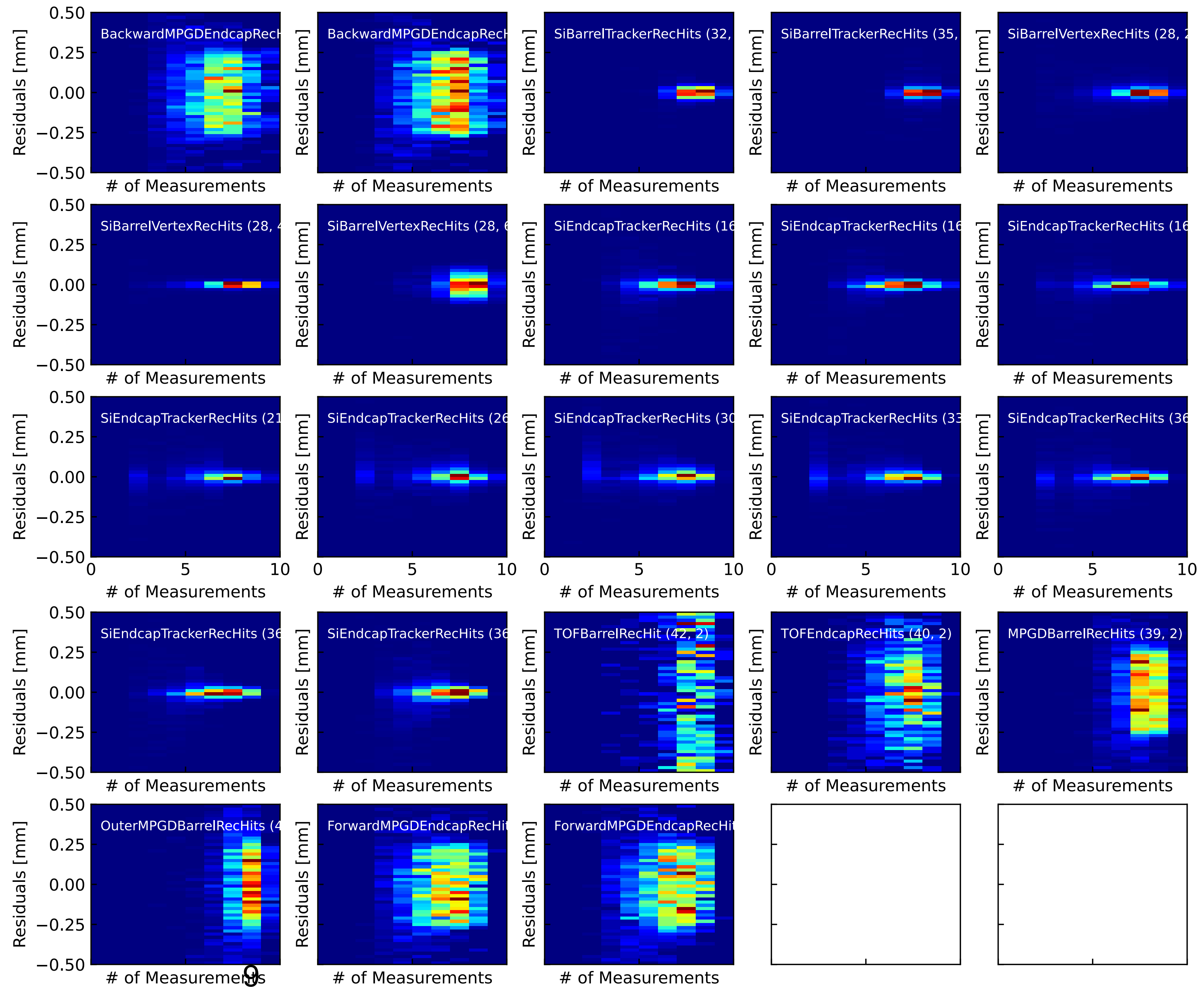
Residuals



Looking at the # of measurements

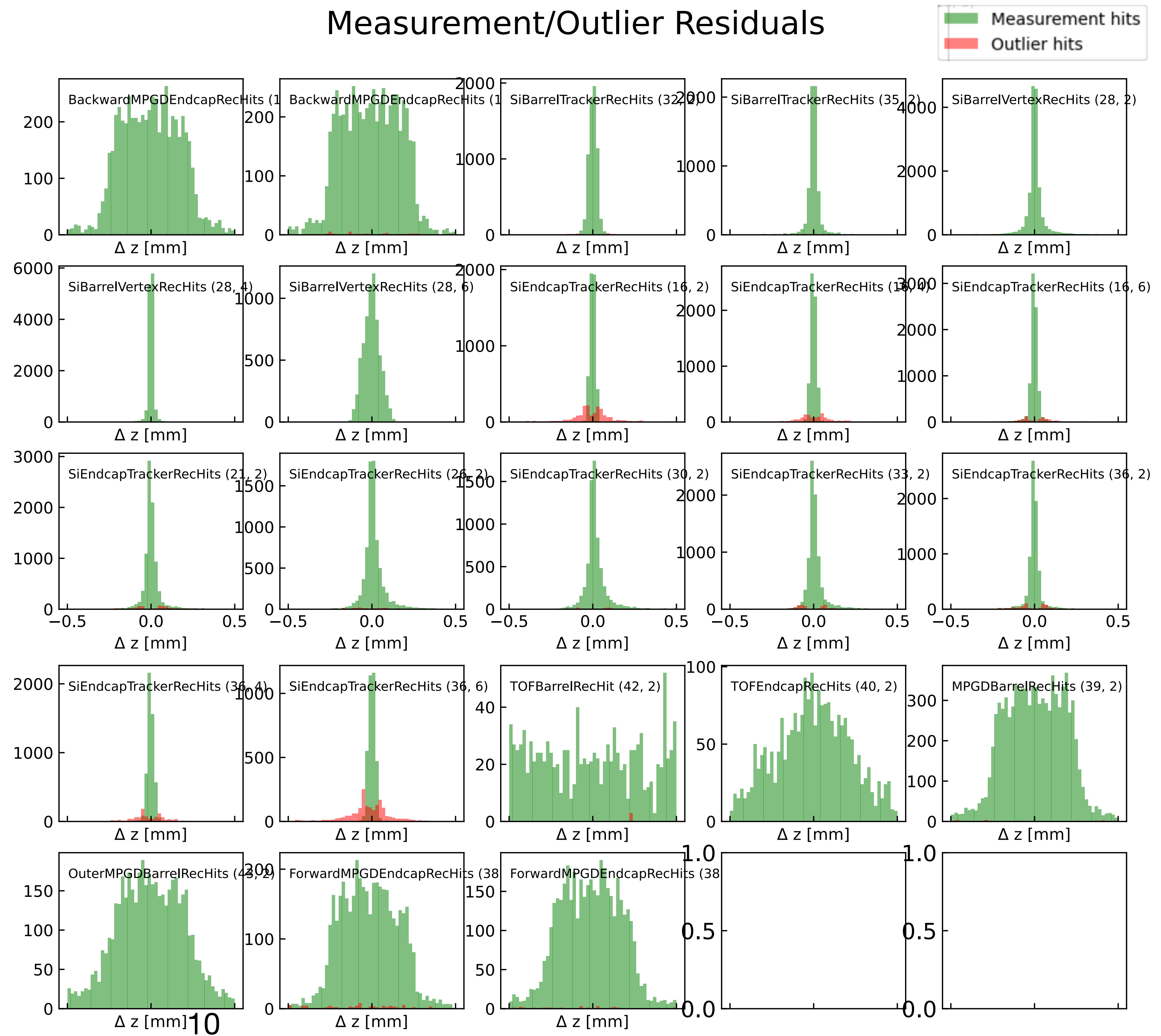
- # of measurements vs residuals
- residuals is a hit quantity, # of meas is a track quantity
- mostly 6-8 hits per track

Measurements vs Residuals



Measurement vs outlier hits

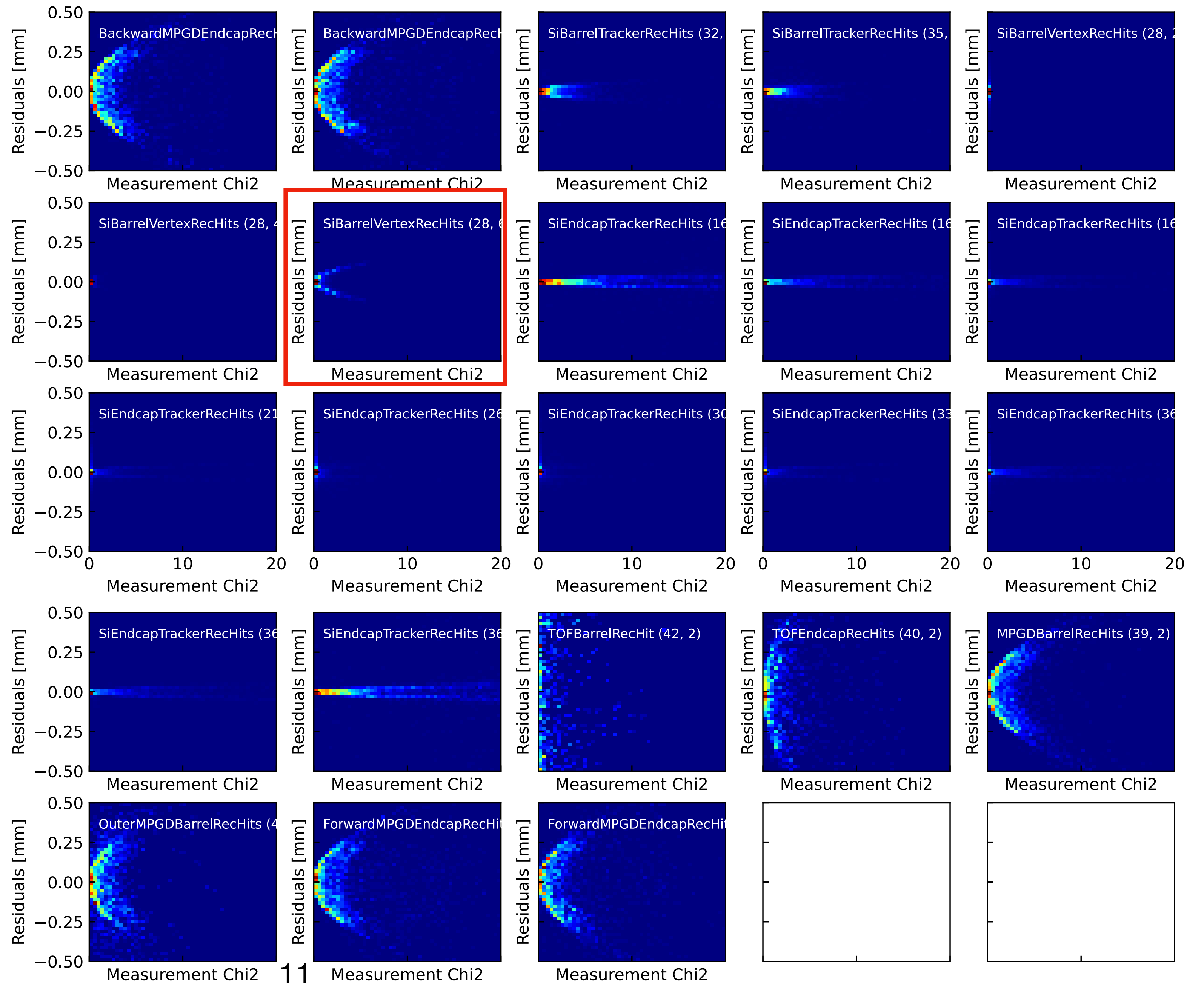
- Wanted to see which hits were used in the final track fit



Measurement Chi²

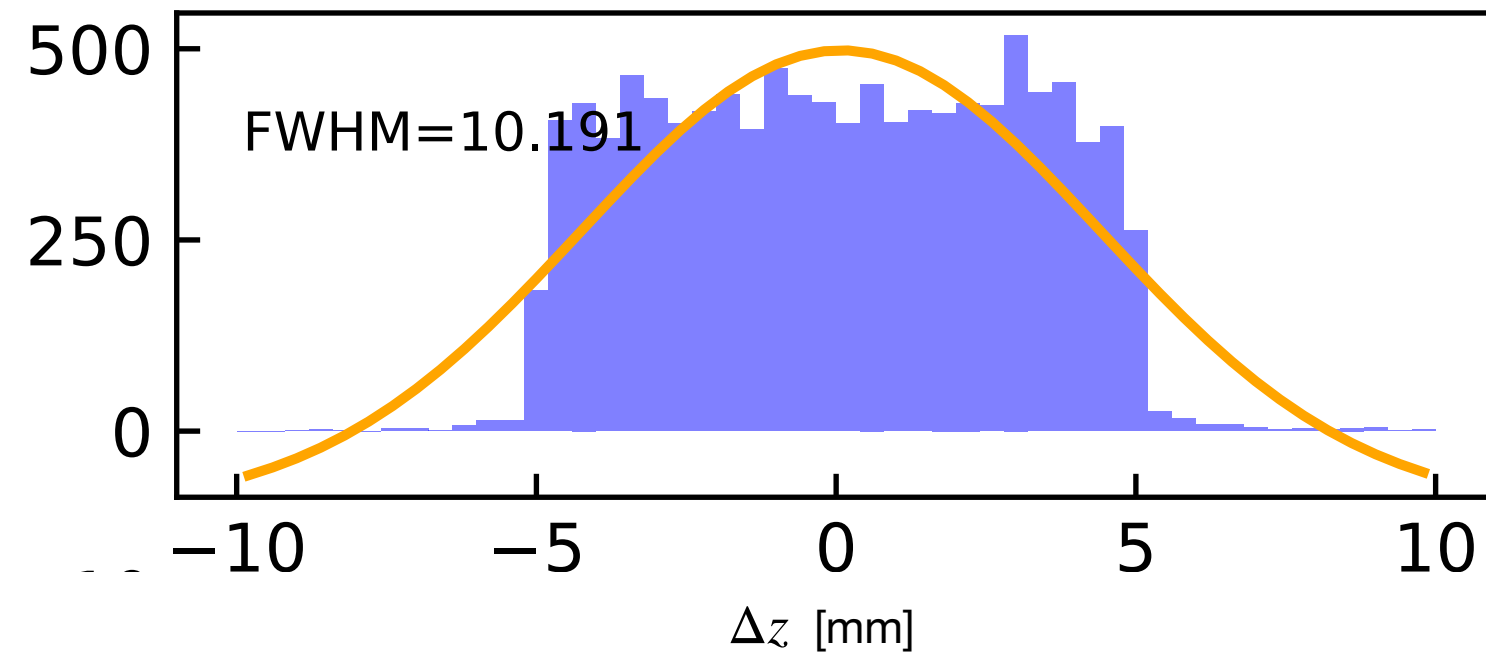
- See more prominent correlation between measurement chi² and the residual in silicon L2

Measurement Chi2 vs Residuals

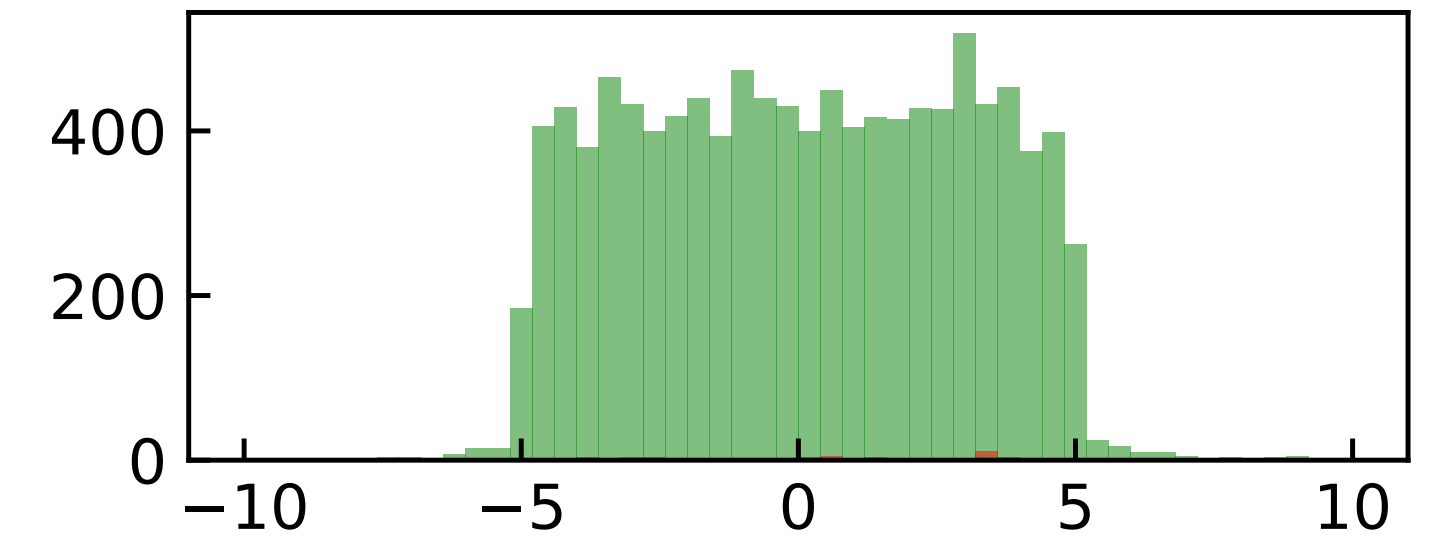


TOF Barrel layer

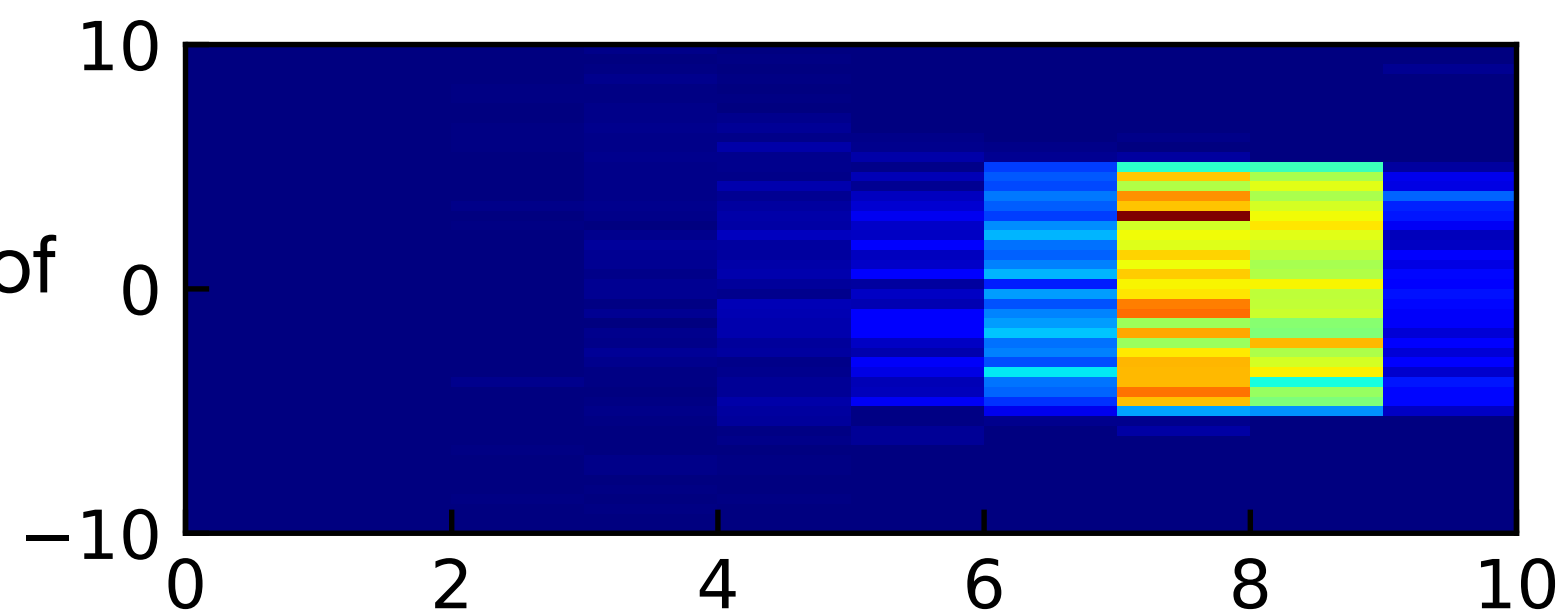
Residuals [mm]:



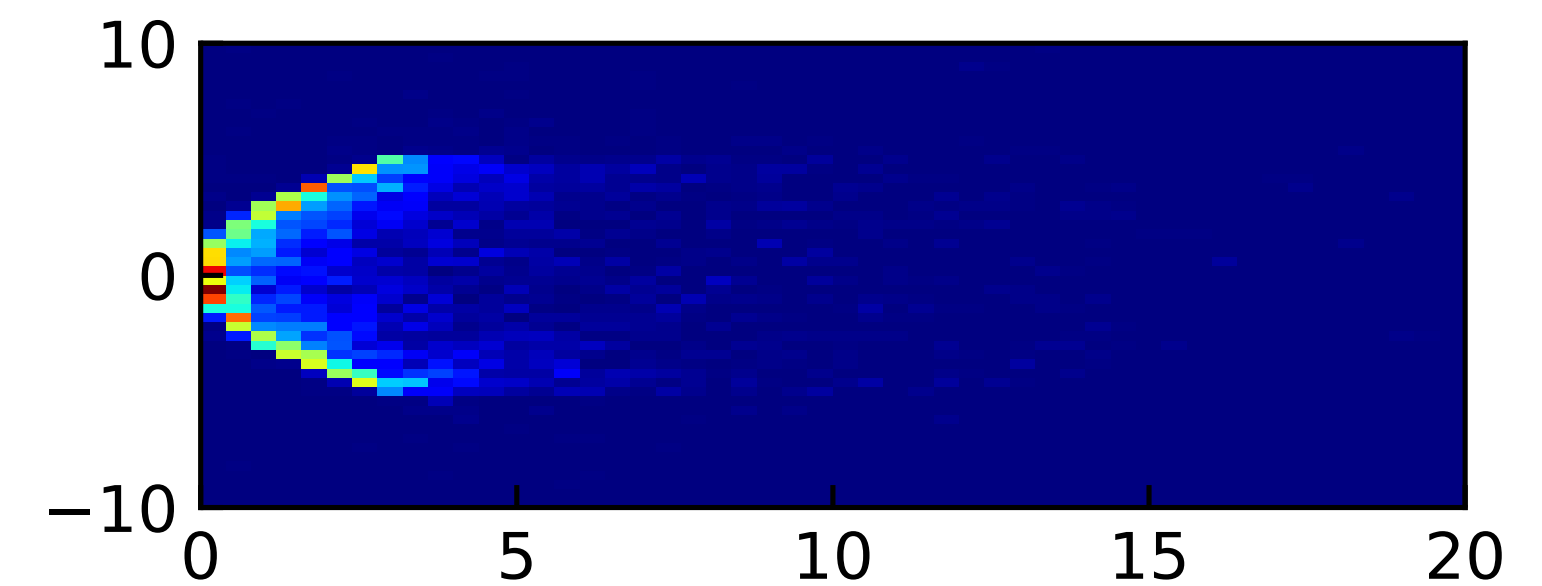
Residuals [mm] for
measurements vs outliers:



Residuals [mm] vs # of
measurements:



Residuals [mm] vs
measurements chi2:



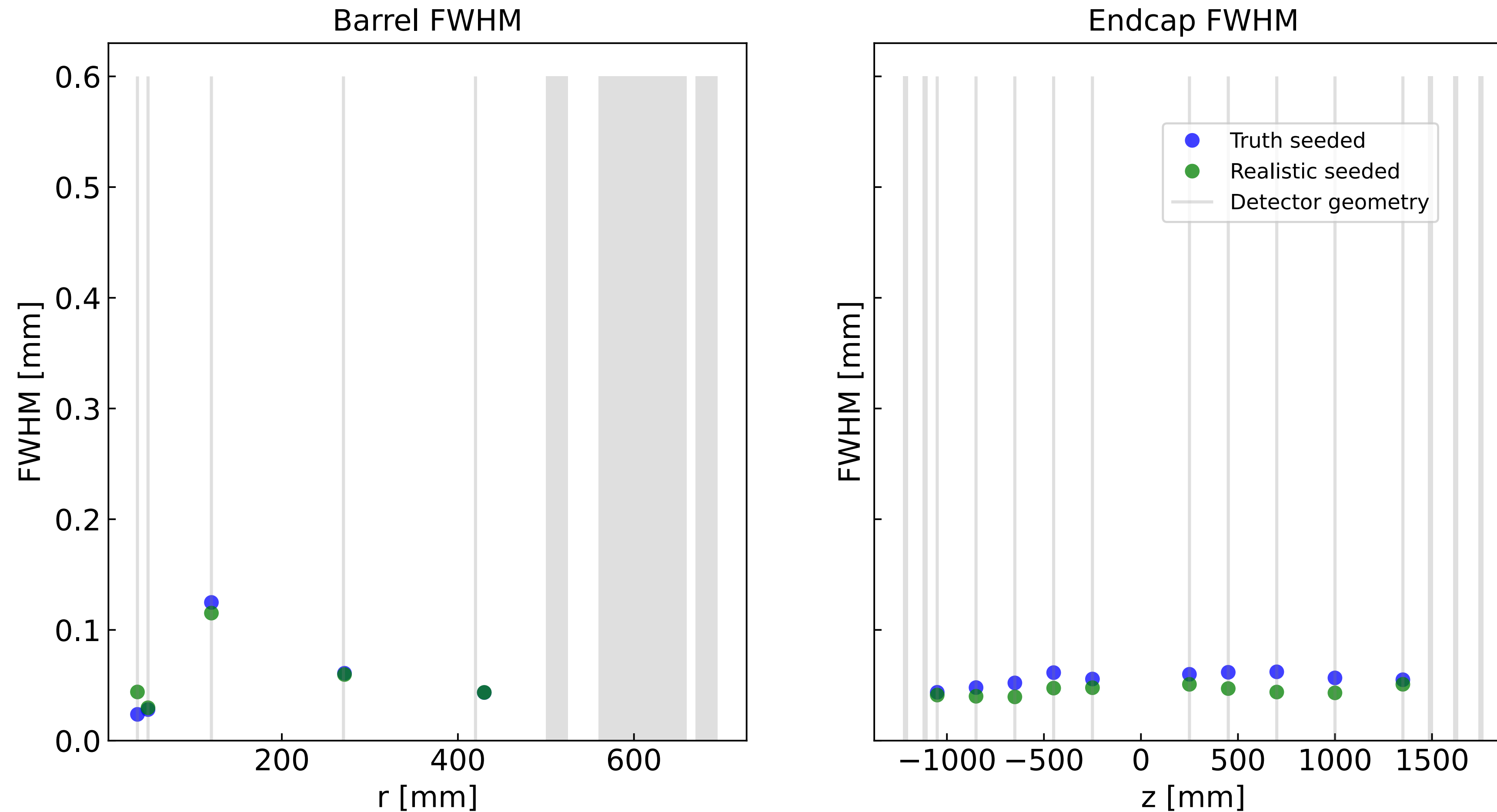
Summary and Next Steps

- Truth & realistic seeded residuals are now easily calculated
- Studied some of the correlations between the measurements and the residuals
- Silicon L2 residual is currently being investigated in further detail

- To do:
 - Make unbiased residuals
 - Some functionality already in ACTS to do this

FWHM at different layers

Full Width at Half Max for Different Layers

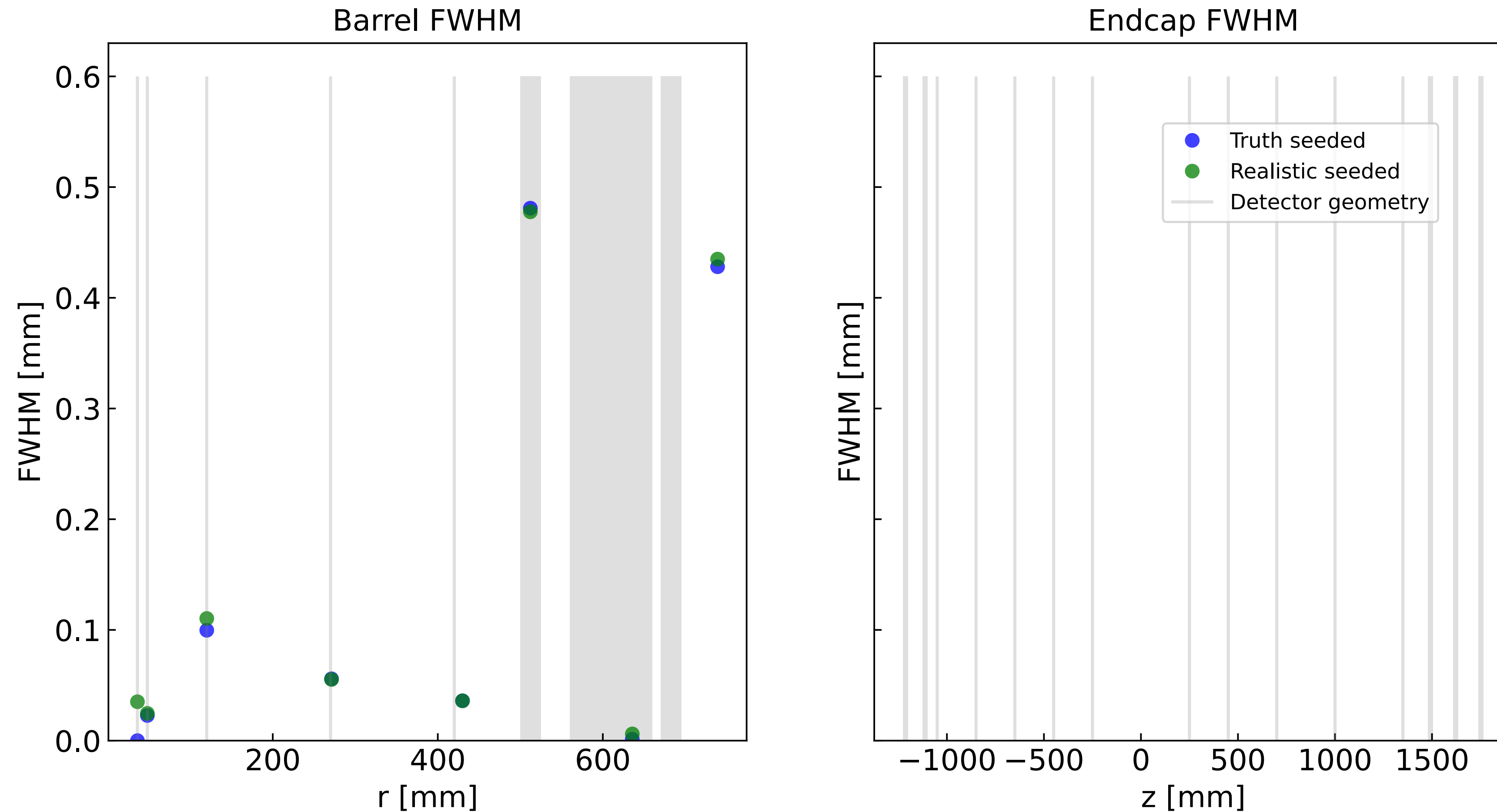


- Not much changed

Single μ^- ,
silicon only
reconstruction

FWHM at different layers

Full Width at Half Max for Different Layers

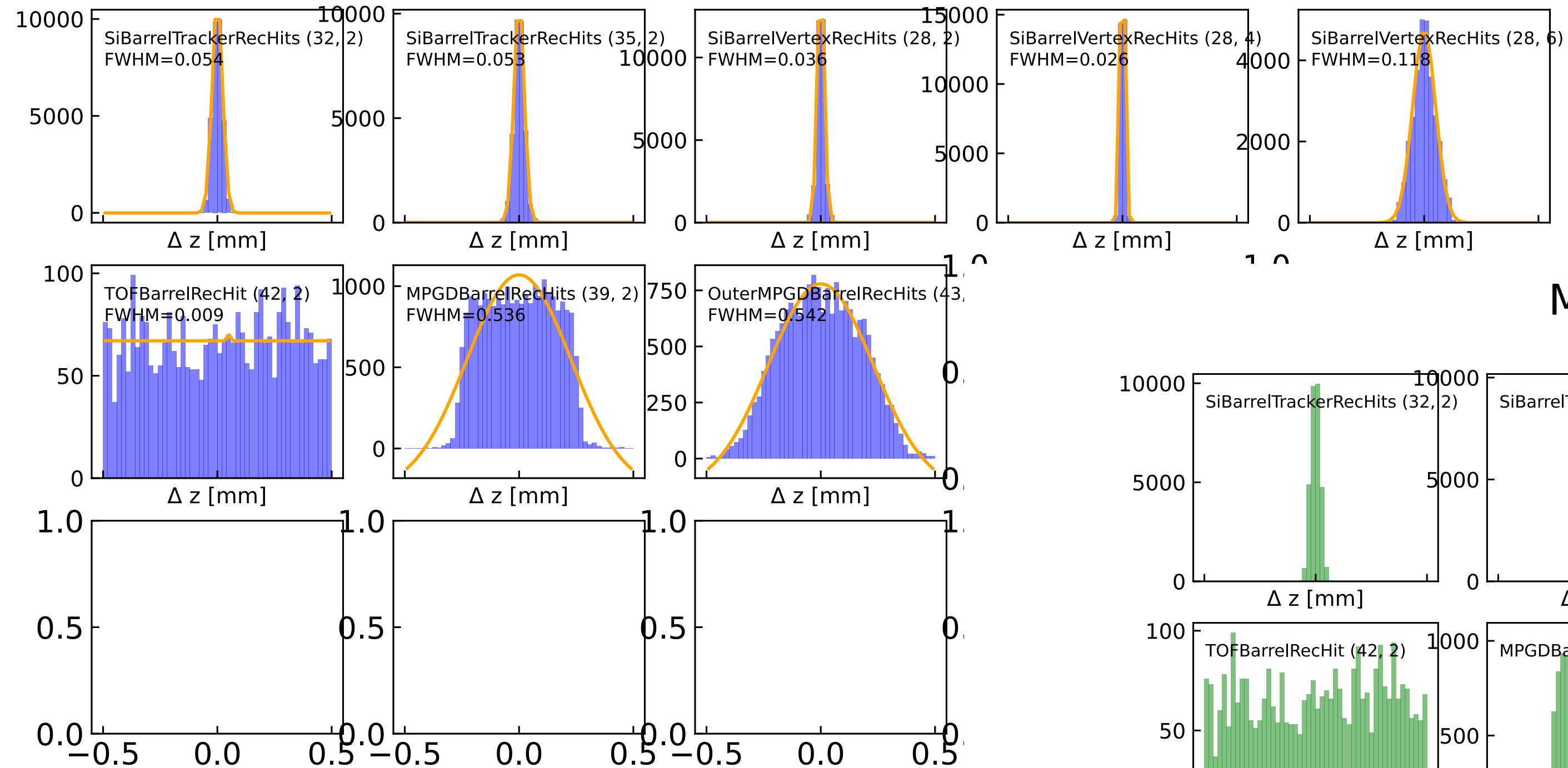


- Only looked at muons that were in the range of $85^\circ < \theta < 95^\circ$

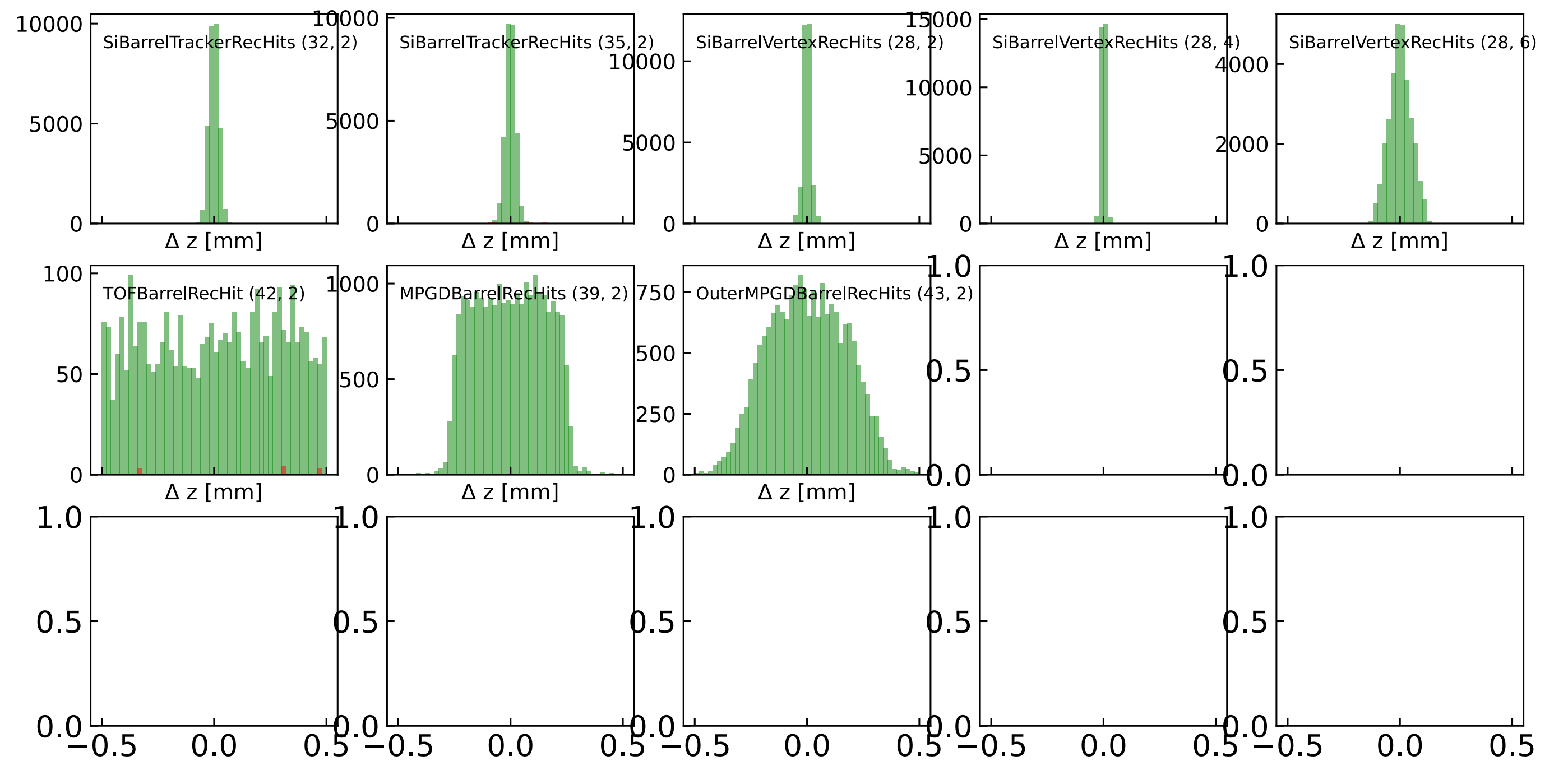
Single μ^- ,
full reconstruction

90 degree muons

Residuals

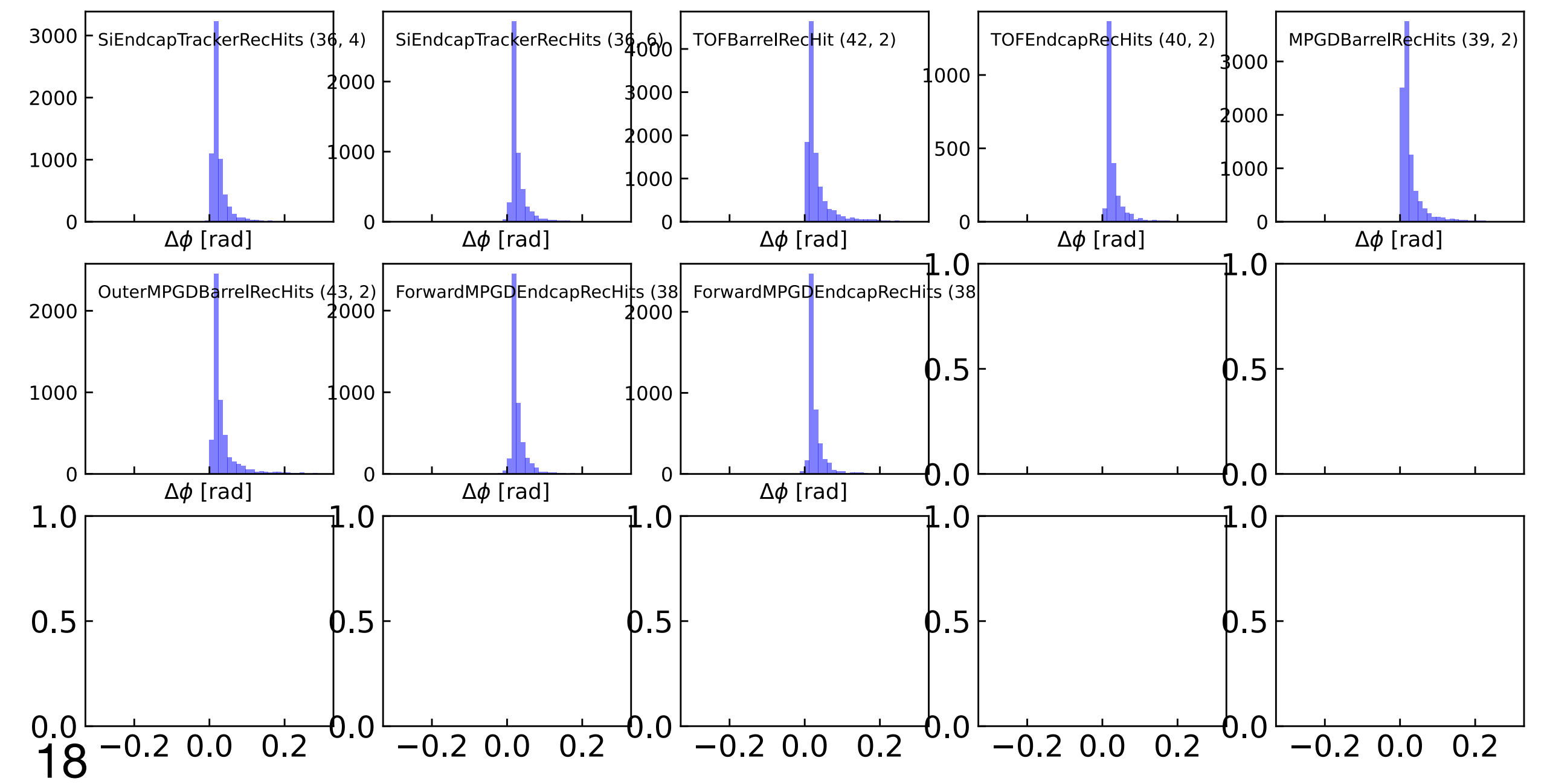
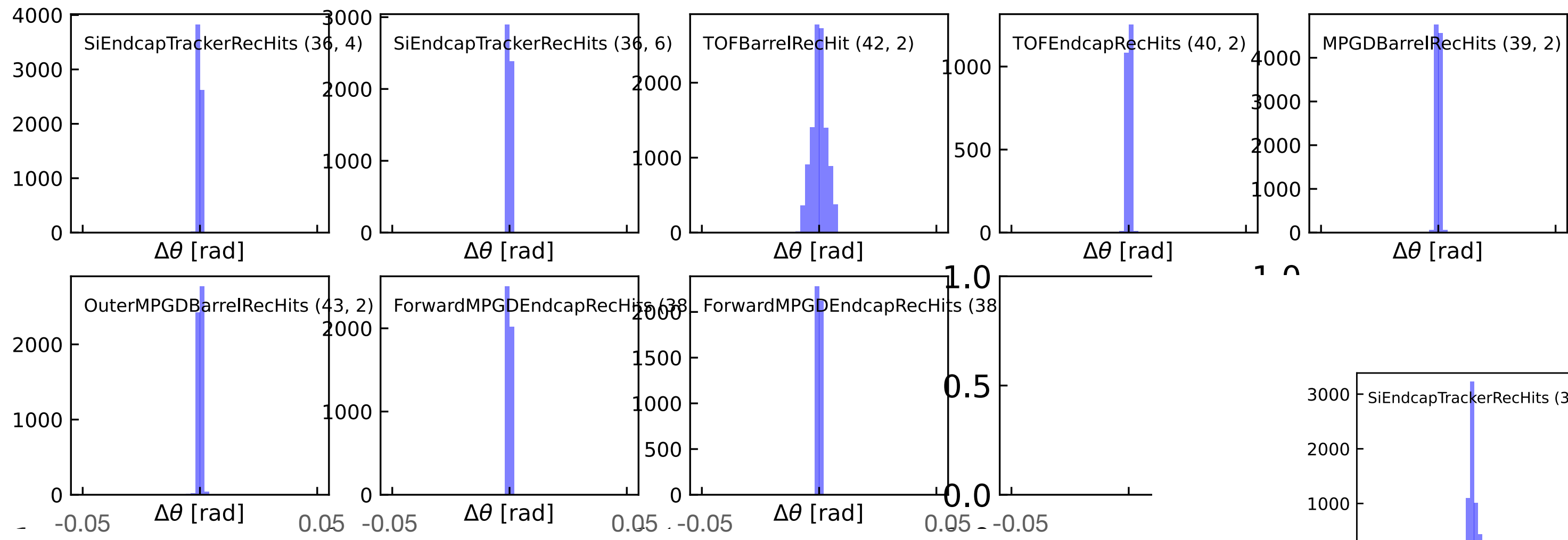
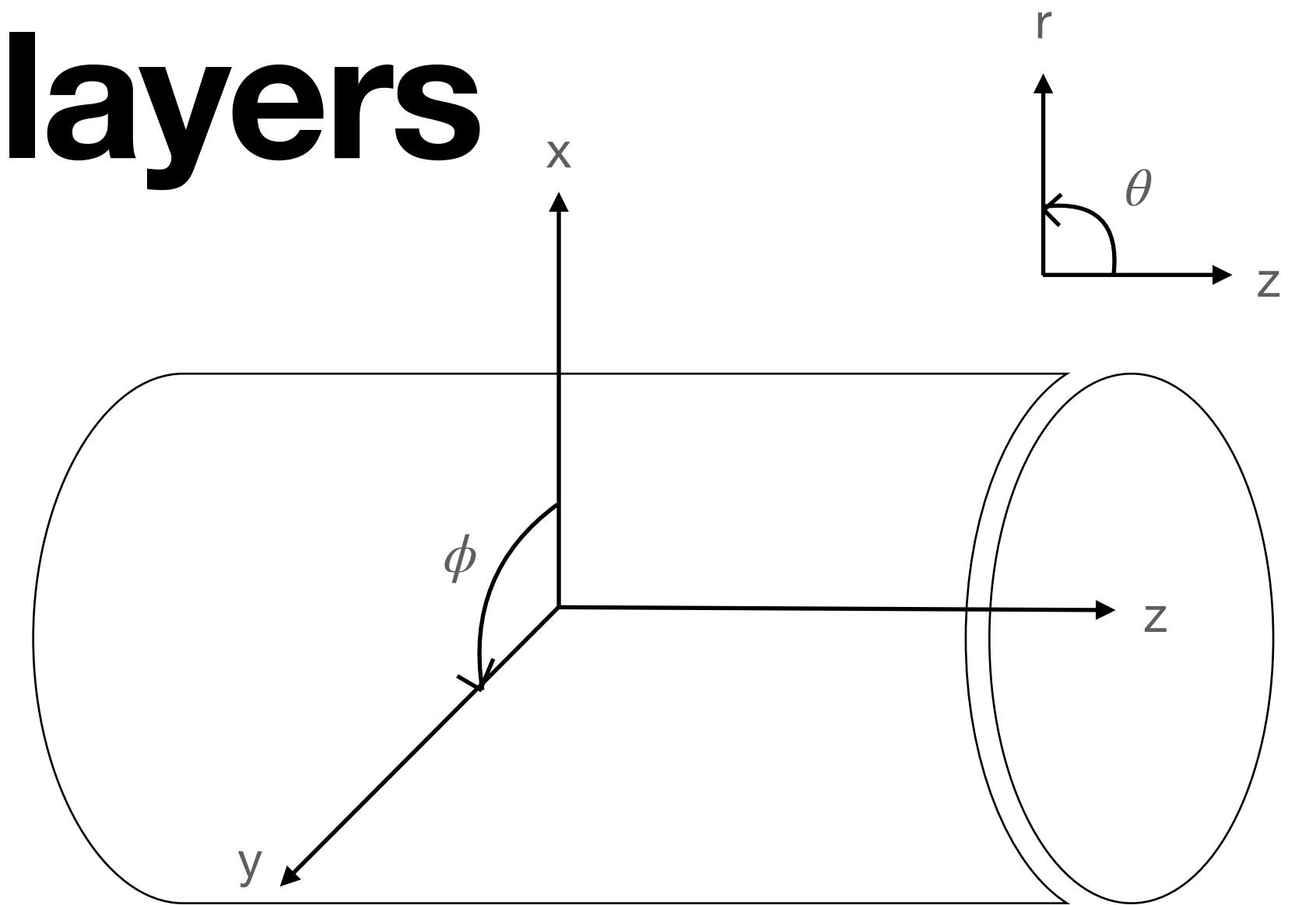


Measurement/Outlier Residuals



Angular residuals, remaining layers

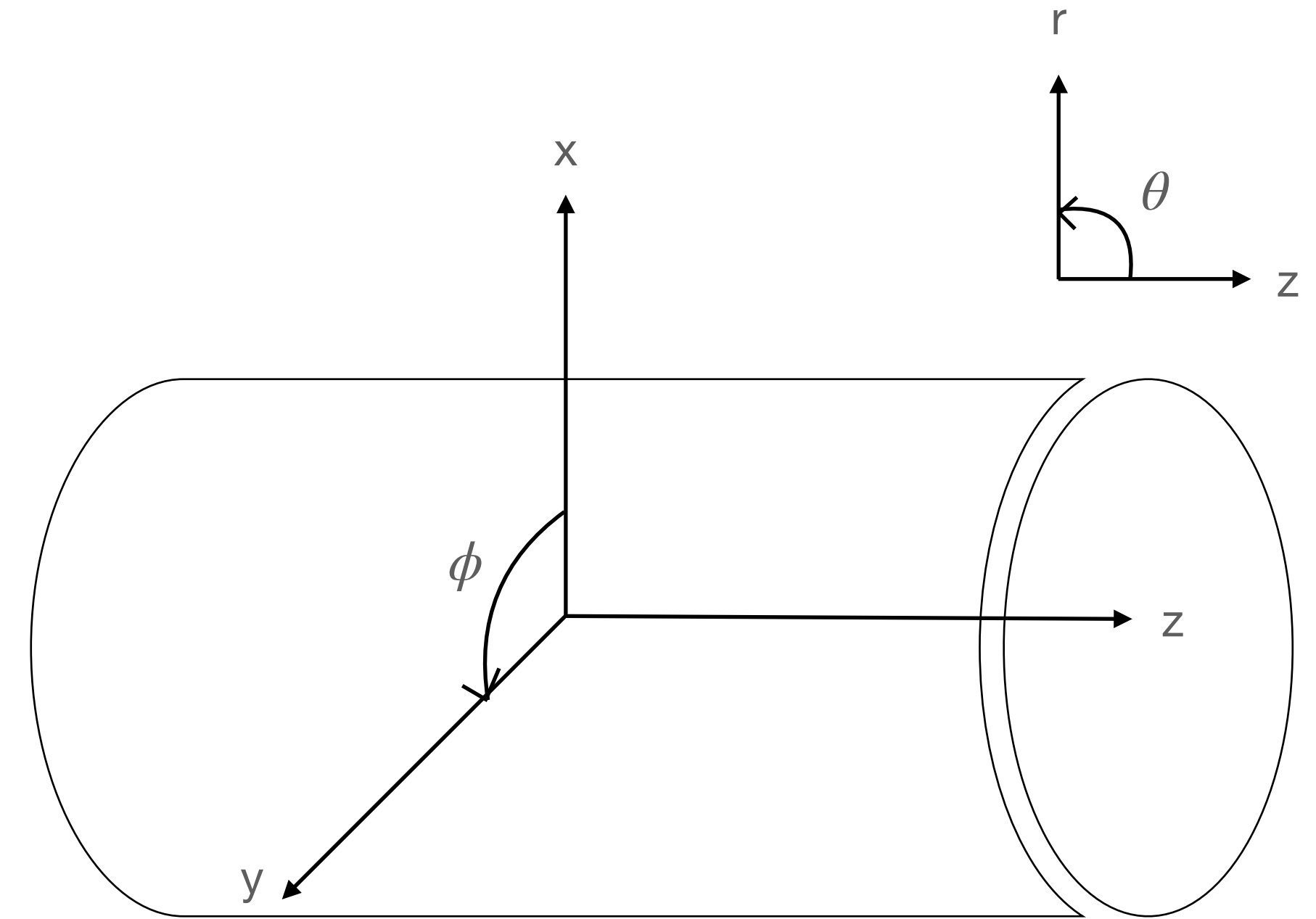
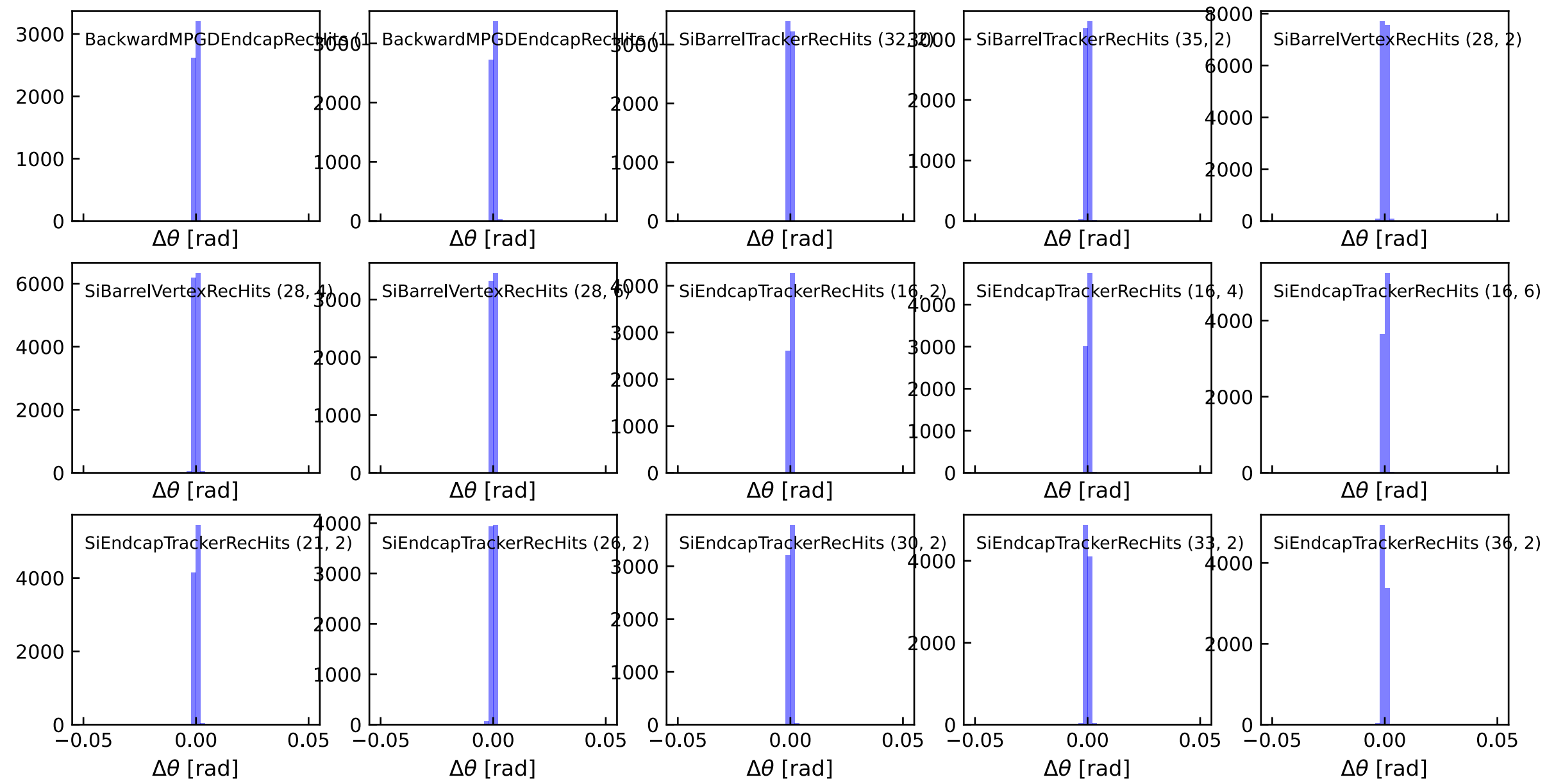
per layer



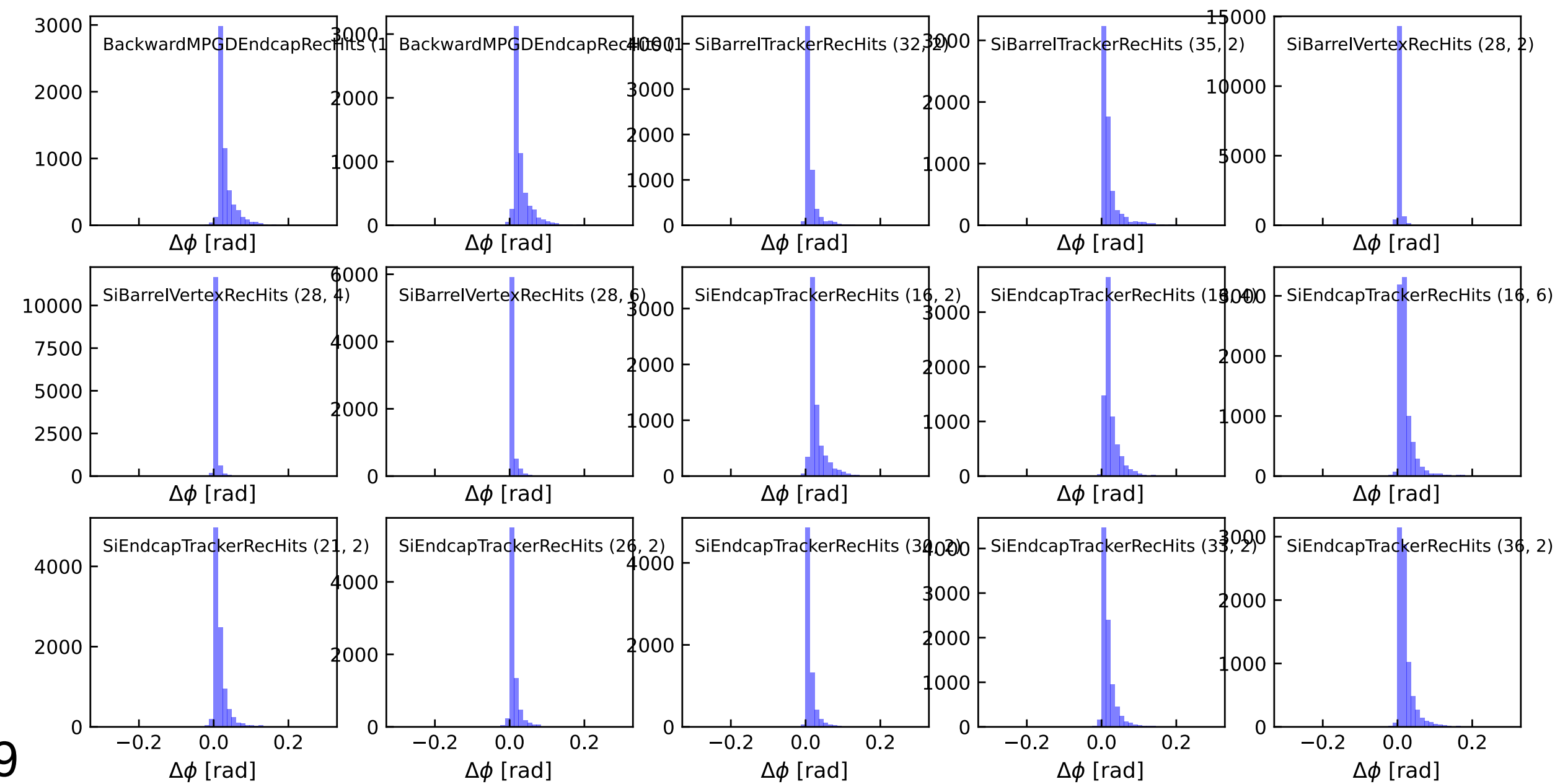
- Quick look at finding the difference in θ and ϕ

Angular residuals per layer

Angular Residuals



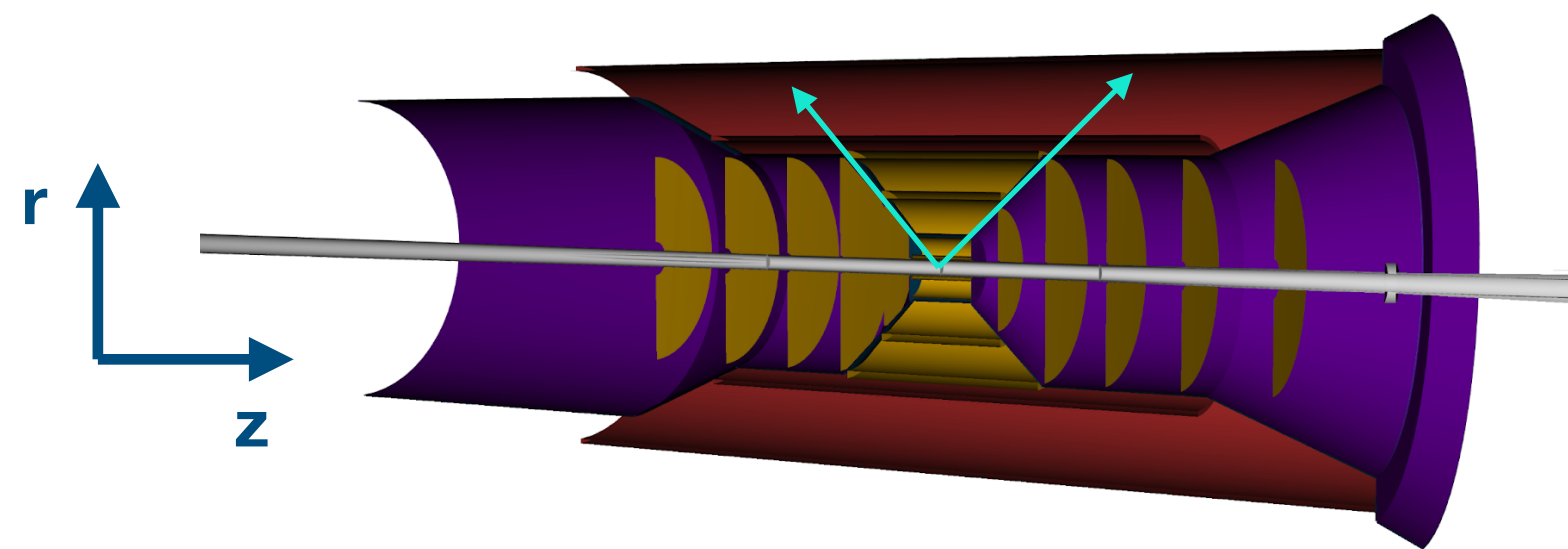
Angular Residuals



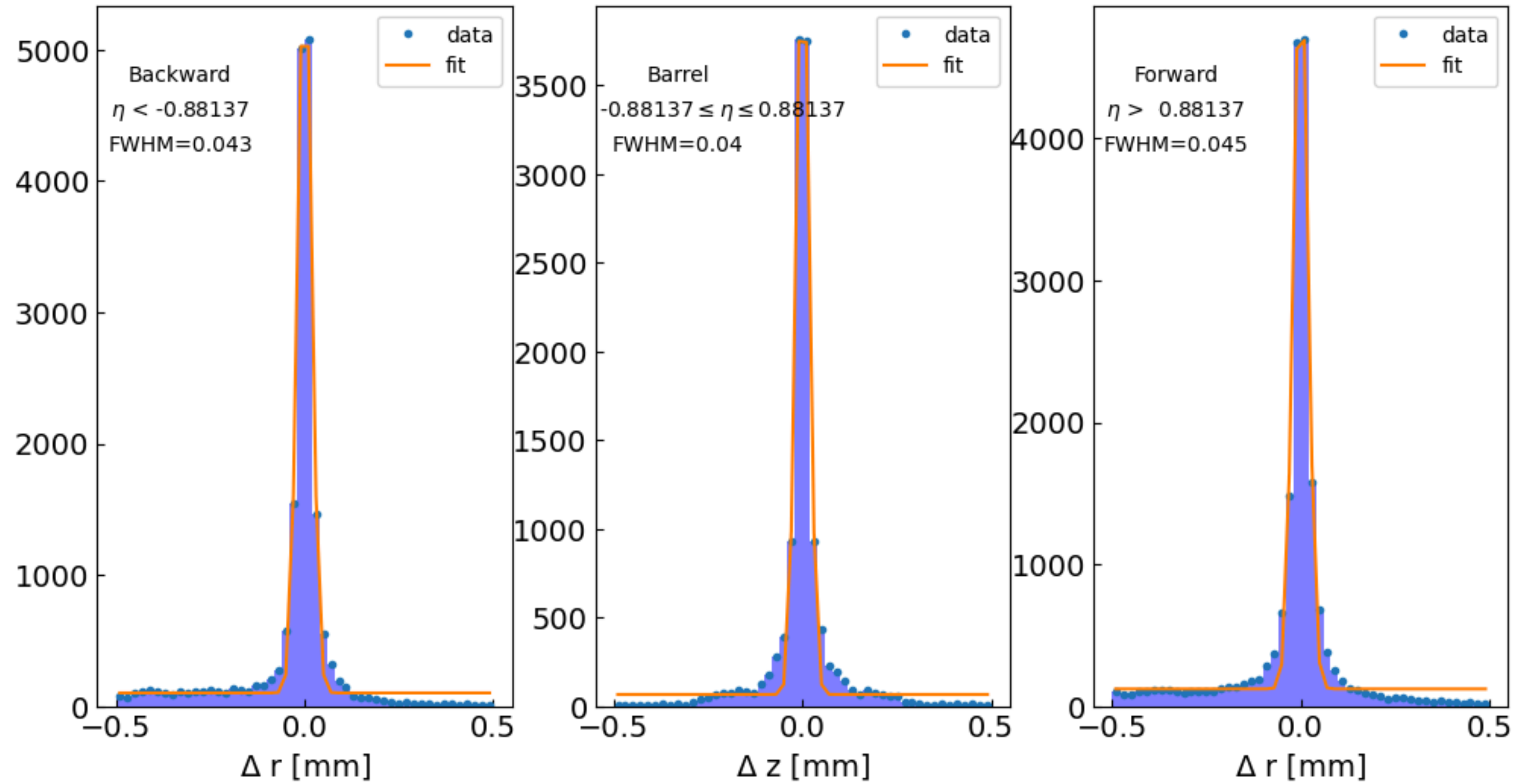
- Quick look at finding the difference in θ and ϕ

Residuals per eta region

- Residuals shown for different eta regions



Residuals



The different collections

- Barrel:
 - SiBarrelTrackerRecHits
 - SiBarrelVertexRecHits
 - TOFBarrelRecHit
 - MPGDBarrelRecHits
 - MPGDDIRCREcHits
 - OuterMPGDBarrelRecHits
- Other collections ignored for now
- Multiple layers included in a given collection

- Endcap:
 - BackwardMPGDEndcapRecHits
 - SiEndcapTrackerRecHits
 - TOFEndcapRecHits
 - ForwardMPGDEndcapRecHits

